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Packet No.: INTT3POUS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of:

Applicants: Rodney E. Schwartz et al.

Examiner: Joseph Mancuso

Serial No: 08/072,206

Art Unit: 2616

Filing Date: June 4, 1993

Title: INTEGRATED CIRCUIT PROBE CARD INSPECTION SYSTEM

Assistant Commissioner for Patents
Washington, D.C. 20231

RESPONSE TO OFFICE ACTION DATED JULY 8, 1996

96 DEC 20 11:10
GROUP 260

Dear Sir:

Favorable reconsideration of the above-identified application is respectfully requested in view of the following amendments and comments.

A petition and fee for a two-month extension of time to respond to the Office Action is being filed concurrently herewith.

AMENDMENTS

In the Claims:

Please amend claim 8 as follows:

98. (Twice Amended) An apparatus for determining the length of a probe tip included on a spring contact probe having a shank from which said probe tip extends, comprising:

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